ERRATUM

Electron Probe Microanalysis of Ni Silicides Using Ni-L X-Ray Lines - ERRATUM

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A typographical error was published in an equation on p. 8 of “Electron Probe Microanalysis of Ni Silicides Using Ni-L X-Ray Lines” by Llovet et al. (2016), whereby a “1” was mistakenly input as a “0”. The corrected sentence and equation is published below:

Notice that \( \omega_{1L} + a_{L2} + f_{L2} = 1 \), where \( a_{L2} \) is the Auger yield for the \( L_2 \) subshell.

We apologize for this error.

REFERENCE